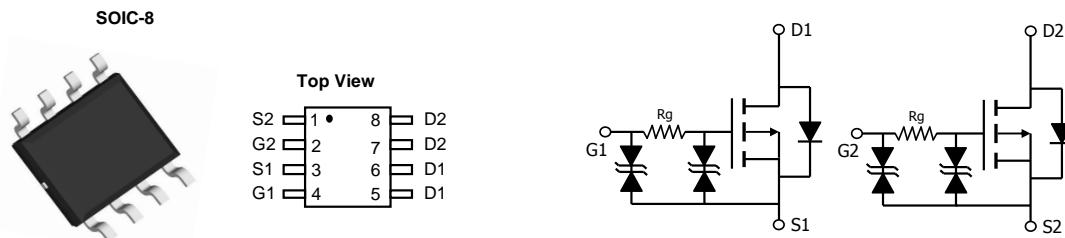


## General Description

The AO4821 uses advanced trench technology to provide excellent  $R_{DS(ON)}$  low gate charge and operation with gate voltages as low as 1.8V. This device is suitable for use as a load switch.

## Features

$V_{DS}$	-12V
$I_D$ (at $V_{GS}=-4.5V$ )	-9A
$R_{DS(ON)}$ (at $V_{GS}=-4.5V$ )	< 19mΩ
$R_{DS(ON)}$ (at $V_{GS}=-2.5V$ )	< 24mΩ
$R_{DS(ON)}$ (at $V_{GS}=-1.8V$ )	< 30mΩ



### Absolute Maximum Ratings $T_A=25^\circ C$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	$V_{DS}$	-12	V
Gate-Source Voltage	$V_{GS}$	$\pm 8$	V
Continuous Drain Current <sup>A</sup>	$I_D$	-9	A
Current <sup>B</sup>	$I_D$	-7	
Pulsed Drain Current <sup>C</sup>	$I_{DM}$	-60	
Power Dissipation <sup>B</sup>	$P_D$	2	W
Power Dissipation <sup>B</sup>	$P_D$	1.28	
Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 to 150	°C

### Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient <sup>A</sup>	$R_{\theta JA}$	48	62.5	°C/W
Maximum Junction-to-Ambient <sup>A,D</sup>		74	90	°C/W
Maximum Junction-to-Lead	$R_{\theta JL}$	32	40	°C/W

**Electrical Characteristics ( $T_J=25^\circ\text{C}$  unless otherwise noted)**

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$I_D=-250\mu\text{A}, V_{GS}=0\text{V}$	-12			V
$I_{\text{DSS}}$	Zero Gate Voltage Drain Current	$V_{DS}=-12\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$			-1 -5	$\mu\text{A}$
$I_{\text{GSS}}$	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}= \pm 8\text{V}$			$\pm 10$	$\mu\text{A}$
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=-250\mu\text{A}$	-0.35	-0.53	-0.85	V
$I_{\text{D(ON)}}$	On state drain current	$V_{GS}=-4.5\text{V}, V_{DS}=-5\text{V}$	-60			A
$R_{\text{DS(ON)}}$	Static Drain-Source On-Resistance	$V_{GS}=-4.5\text{V}, I_D=-9\text{A}$ $T_J=125^\circ\text{C}$		16	19	$\text{m}\Omega$
		$V_{GS}=-2.5\text{V}, I_D=-8\text{A}$		22	27	
		$V_{GS}=-1.8\text{V}, I_D=-6\text{A}$		19	24	
$g_{\text{FS}}$	Forward Transconductance	$V_{DS}=-5\text{V}, I_D=-9\text{A}$		23	30	$\text{m}\Omega$
$V_{\text{SD}}$	Diode Forward Voltage	$I_S=-1\text{A}, V_{GS}=0\text{V}$		-0.56	-1	V
$I_S$	Maximum Body-Diode Continuous Current				-3	A
<b>DYNAMIC PARAMETERS</b>						
$C_{\text{iss}}$	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=-6\text{V}, f=1\text{MHz}$	1390	1740	2100	$\text{pF}$
$C_{\text{oss}}$	Output Capacitance		230	334	435	$\text{pF}$
$C_{\text{rss}}$	Reverse Transfer Capacitance		120	200	280	$\text{pF}$
$R_g$	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$	0.9	1.3	1.7	$\text{k}\Omega$
<b>SWITCHING PARAMETERS</b>						
$Q_g(4.5\text{V})$	Total Gate Charge	$V_{GS}=-4.5\text{V}, V_{DS}=-6\text{V}, I_D=-9\text{A}$	15	19	23	nC
$Q_{\text{gs}}$	Gate Source Charge		3.6	4.5	5.4	nC
$Q_{\text{gd}}$	Gate Drain Charge		3	5.3	7.4	nC
$t_{\text{D(on)}}$	Turn-On DelayTime	$V_{GS}=-4.5\text{V}, V_{DS}=-6\text{V}, R_L=0.67\Omega, R_{\text{GEN}}=3\Omega$	240			ns
$t_r$	Turn-On Rise Time		580			ns
$t_{\text{D(off)}}$	Turn-Off DelayTime		7			$\mu\text{s}$
$t_f$	Turn-Off Fall Time		4.2			$\mu\text{s}$
$t_{\text{rr}}$	Body Diode Reverse Recovery Time	$I_F=-9\text{A}, dI/dt=500\text{A}/\mu\text{s}$	18	22	26	ns
$Q_{\text{rr}}$	Body Diode Reverse Recovery Charge	$I_F=-9\text{A}, dI/dt=500\text{A}/\mu\text{s}$	14	17	20	nC

A. The value of  $R_{\text{0JA}}$  is measured with the device mounted on  $1\text{in}^2$  FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The value in any given application depends on the user's specific board design.

B. The power dissipation  $P_D$  is based on  $T_{J(\text{MAX})}=150^\circ\text{C}$ , using  $\leq 10\text{s}$  junction-to-ambient thermal resistance.

C. Repetitive rating, pulse width limited by junction temperature  $T_{J(\text{MAX})}=150^\circ\text{C}$ . Ratings are based on low frequency and duty cycles to keep initial  $T_J=25^\circ\text{C}$ .

D. The  $R_{\text{0JA}}$  is the sum of the thermal impedance from junction to lead  $R_{\text{0UL}}$  and lead to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using  $<300\mu\text{s}$  pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-ambient thermal impedance which is measured with the device mounted on  $1\text{in}^2$  FR-4 board with 2oz. Copper, assuming a maximum junction temperature of  $T_{J(\text{MAX})}=150^\circ\text{C}$ . The SOA curve provides a single pulse rating.

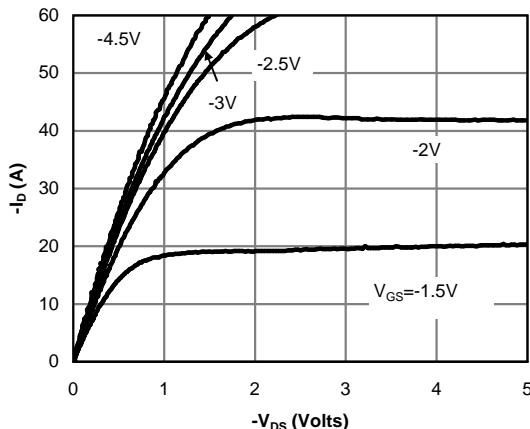
**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**


Fig 1: On-Region Characteristics (Note E)

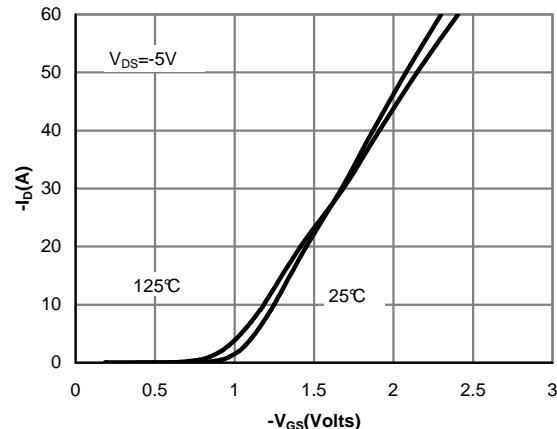


Figure 2: Transfer Characteristics (Note E)

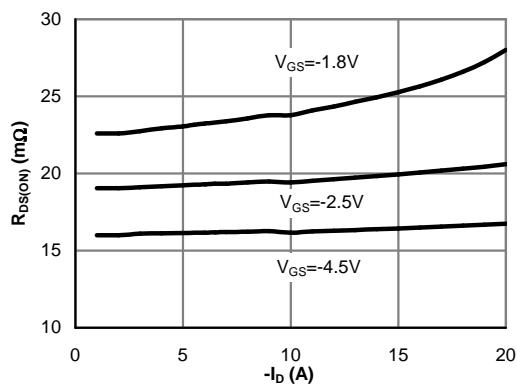


Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

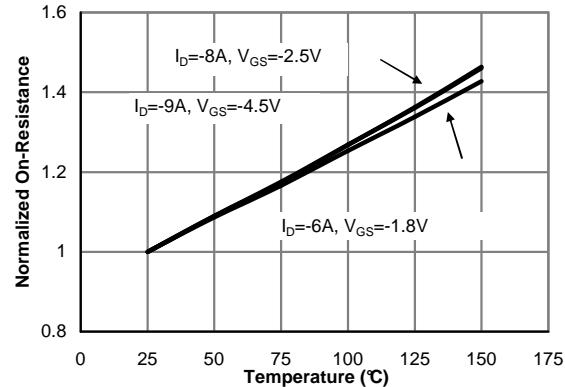


Figure 4: On-Resistance vs. Junction Temperature (Note E)

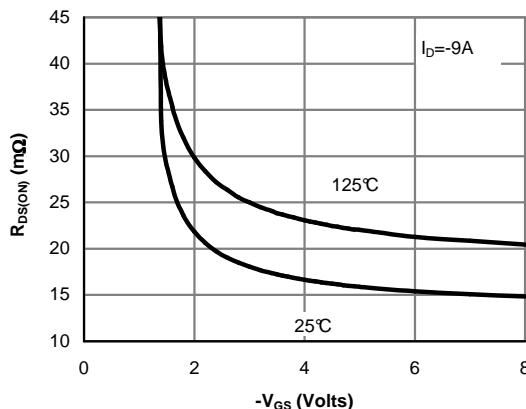


Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

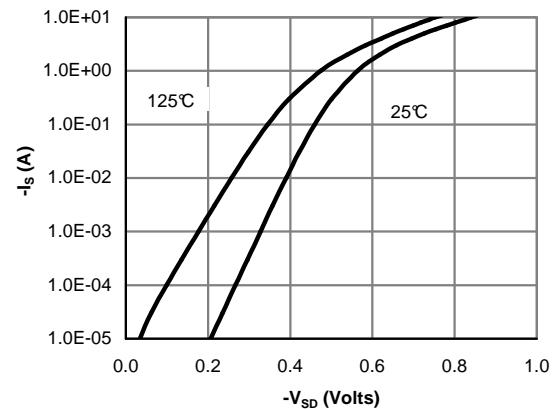
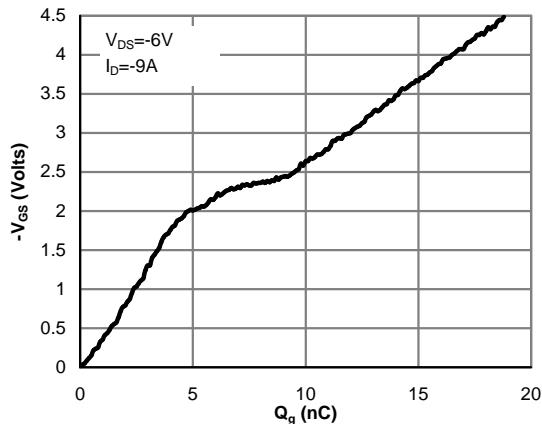
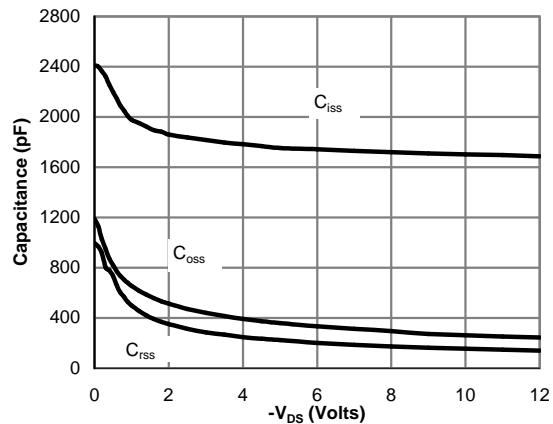
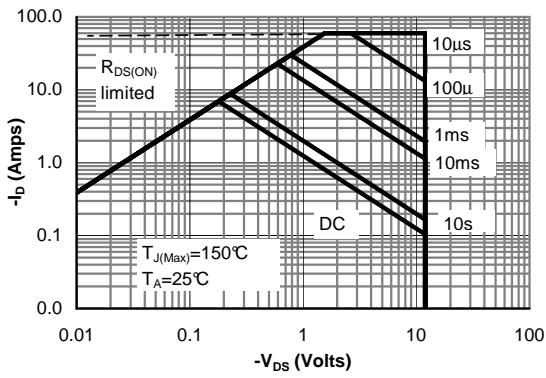
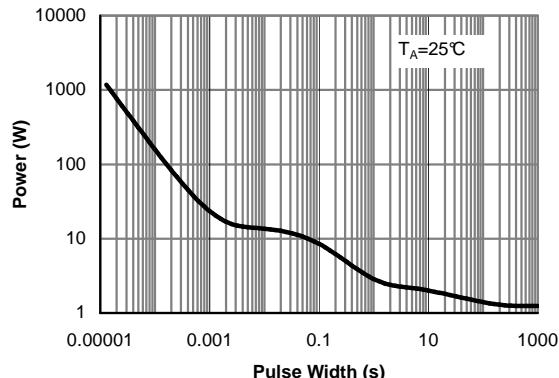
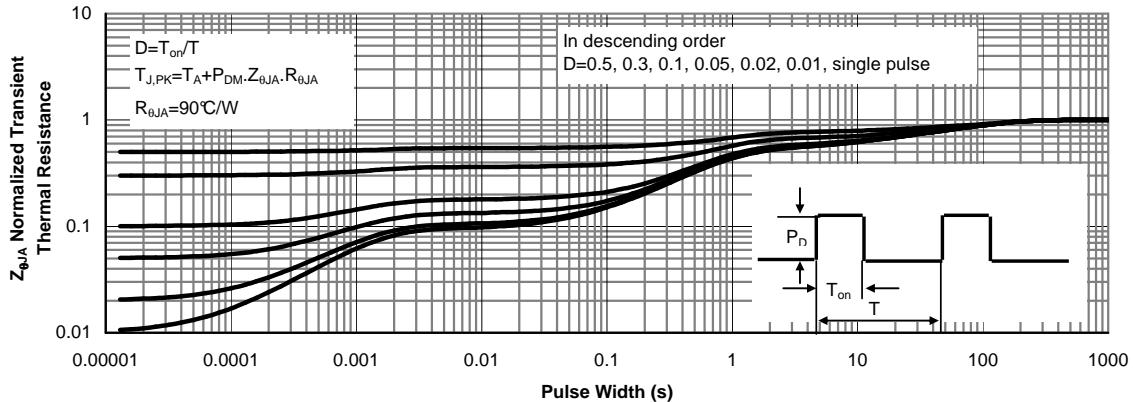
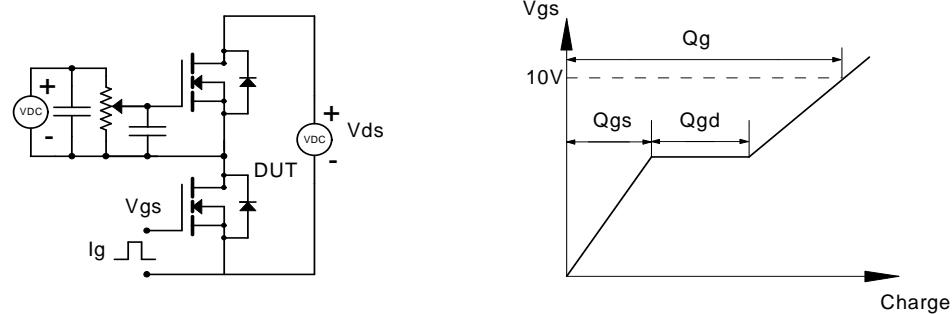


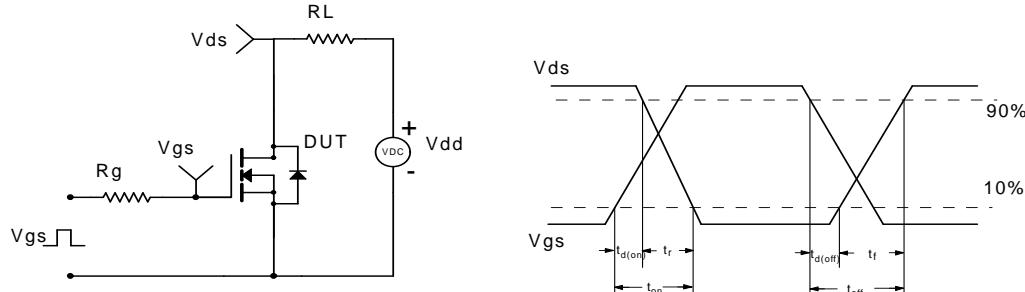
Figure 6: Body-Diode Characteristics (Note E)

**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**

**Figure 7: Gate-Charge Characteristics**

**Figure 8: Capacitance Characteristics**

**Figure 9: Maximum Forward Biased Safe Operating Area (Note F)**

**Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note F)**

**Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)**

Gate Charge Test Circuit &amp; Waveform



Resistive Switching Test Circuit &amp; Waveforms



Diode Recovery Test Circuit &amp; Waveforms

